

Title (en)

SEMICONDUCTOR LAYER SEQUENCE AND METHOD FOR PRODUCING THE SAME

Title (de)

HALBLEITERSCHICHTENFOLGE UND VERFAHREN ZU DEREN HERSTELLUNG

Title (fr)

SUCCESION DE COUCHES DE SEMI-CONDUCTEURS ET PROCÉDÉ DE FABRICATION DE CELLE-CI

Publication

EP 3069389 A1 20160921 (DE)

Application

EP 14799686 A 20141104

Priority

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- EP 2014073717 W 20141104

Abstract (en)

[origin: WO2015071134A1] In at least one embodiment, the semiconductor layer sequence (10) has an n-conducting n side (11), a p-conducting p side (13) and an active zone (2) lying in between. The active zone (2) has at least one radiation-active layer (21) with a first material composition for generating a first radiation (L1). The at least one radiation-active layer (21) is oriented perpendicularly to a direction of growth (z) of the semiconductor layer sequence. Furthermore, the active zone (2) has a multiplicity of radiation-active tubes (22) with a second material composition or a different crystal structure for generating a second radiation (L2), wherein the second material composition is different from the first material composition. The radiation-active tubes (22) are oriented parallel to the direction of growth (z).

IPC 8 full level

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CPC (source: EP US)

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Citation (search report)

See references of WO 2015071134A1

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